TOSHIBA Photocoupler G aAs IRed & Photo-Triac

# TLP525G,TLP525G-2,TLP525G-4

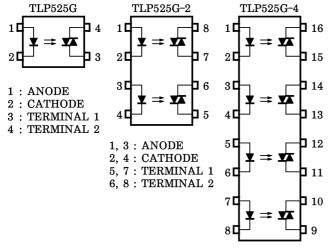
Triac Drive
Programmable Controllers
AC-Output Module
Solid State Relay

The TOSHIBA TLP525G, -2 and -4 consist of a photo–triac optically coupled to a gallium arsenide infrared emitting diode.

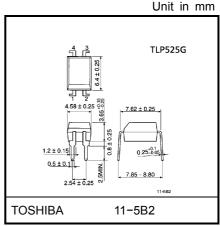
The TLP525G-2 offers two isolated channels in an eight lead plastic DIP package, while the TLP525G-4 provides four isolated channels in a sixteenn lead plastic DIP package.

- Peak off-stage voltage: 400V (min.)
- Trigger LED current: 10mA (max.)
- Peak on-stage current: 2Apk (max.)
- Isolation voltage: 2500V<sub>rms</sub> (min.)
- UL recognized: File no.E67349

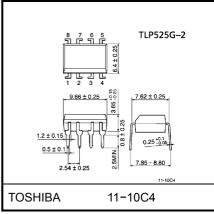
#### Pin Configurations (top view)



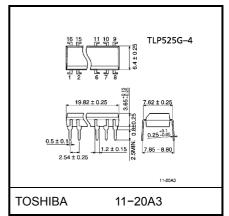
1, 3, 5, 7 : ANODE 2, 4, 6, 8 : CATHODE 9, 11, 13, 15 : TERMINAL 1 10, 12, 14, 16 : TERMINAL 2



Weight: 0.26g



Weight: 0.54g



Weight: 1.1g



### **Maximum Ratings (Ta = 25°C)**

Characteristic S				Ra		
			ymbol	TLP525G	TLP525G-2 TLP525G-4	Unit
CED	Forward current		lF	50	50	mA
	Forward current derating		I <sub>F</sub> / °C	-0.7 (Ta ≥ 53°C)	–0.5 (Ta ≥ 25°C)	mA / °C
	Pulse forward current		I <sub>FP</sub>	1 (100µs pulse, 100pps)		Α
	Reverse voltage		V <sub>R</sub>	5		V
	Junction temperature		Tj	125 °		С
	Off–state output terminal voltage		$V_{DRM}$	400		V
	On-state RMS current	Ta = 25°C	la (Duo)	100	80	mA
_		Ta = 70°C	I <sub>T (RMS)</sub>	50 40		IIIA
Detector	On–state current derating (Ta≥25°C)		I <sub>T</sub> / °C	-1.1	-0.9	mA / °C
	Peak on state current		I <sub>TP</sub>	2 (100µs pulse, 120pps)		Α
	Peak nonrepetitive surge current (P <sub>W</sub> = 10ms, DC = 10%)		I <sub>TSM</sub>	1.2 A		
	Junction temperature		Tj	115		°C
Storage temperature range			T <sub>stg</sub>	-55~125		°C
Operating temperature range		T <sub>opr</sub>	-40~100		°C	
Lead soldering temperature		T <sub>sol</sub>	260 (10s)		°C	
Isola	Isolation voltage (Note)		BVS	2500 (AC, 1min., R.H. ≤ 60%)		V <sub>rms</sub>

(Note) Device considered a two terminal device: LED side pins shorted together and detector side pins shorted togeth er.

### **Recommended Operating Conditions**

Characteristic S	ymbol	Min.	Тур.	Max.	Unit
Supply voltage	V <sub>AC</sub>	_	_	120	Vac
Forward current	lF	15	20	25	mA
Peak on-state current	I <sub>TP</sub>	_	_	1	Α
Operating temperature	T <sub>opr</sub>	-25	_	85	°C



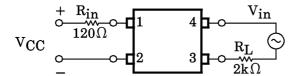
# Individual Electrical Characteristics (Ta = 25°C)

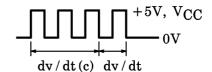
Characteristic S		ymbol	Test Condition	Min.	Тур.	Max.	Unit
LED	Forward voltage	V <sub>F</sub>	I <sub>F</sub> = 10mA	1.0	1.15	1.3	V
	Reverse current	I <sub>R</sub>	V <sub>R</sub> = 5V			10 μ	Α
	Capacitance C	Т	V = 0, f = 1MHz	— 30		— pF	
	Peak off-state current	I <sub>DRM</sub>	V <sub>DRM</sub> = 400V	_ 10		100 n/	4
	Peak on-state voltage	V <sub>TM</sub>	I <sub>TM</sub> = 100mA	_	1.7 3.	0	V
Detector	Holding current	lΗ	_	<b>—</b> 0.	2	_	mA
	Critical rate of rise of off–state voltage	dv / dt	V <sub>in</sub> = 120V <sub>rms</sub> , Ta = 85°C (Fi gure 1)	200	500	-	V / µs
	Critical rate of rise of commutating voltage	dv / dt (c)	$V_{in}$ = 30 $V_{rms}$ , $I_T$ = 15mA gure 1)	<b>—</b> 0.	2	_ v	/ µs

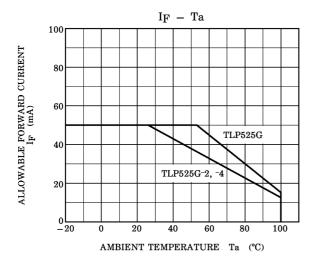
# **Coupled Electrical Characteristics (Ta = 25°C)**

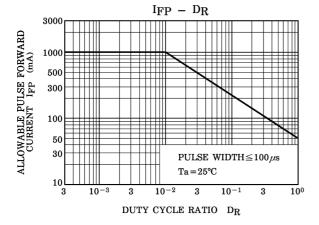
Characteristic S	ymbol	Test Condition	Min.	Тур.	Max.	Unit
Trigger LED current	I <sub>FT</sub>	V <sub>T</sub> = 3V	<b>—</b> 5		10 m	Α
Capacitance input to output	C <sub>S</sub>	V <sub>S</sub> = 0, f = 1MHz	<b>—</b> 0.	8	— pF	
Isolation resistance	R <sub>S</sub>	V <sub>S</sub> = 500V, R.H. ≤ 60%	5×10 <sup>10</sup>	10 <sup>14</sup>	_	Ω
	BVS	AC, 1 minute	2500	_	_	Vrms
Isolation voltage		AC, 1 second, in oil	<b>—</b> 500	<b>—</b> 5000		VIIIIS
		DC, 1 minute, in oil	— 500	0	— Vd	С

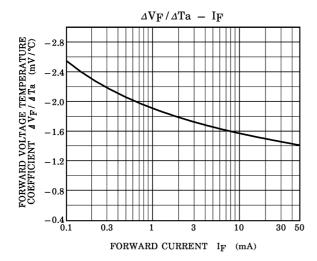
Fig.1 dv / dt Test Circuit

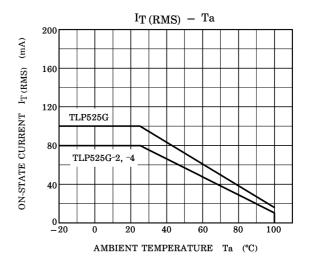


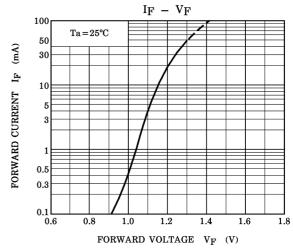


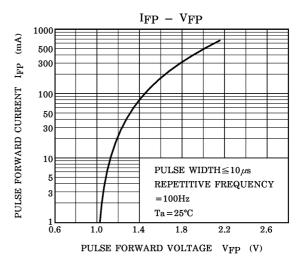




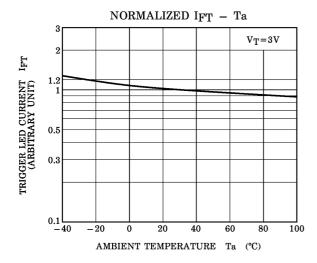


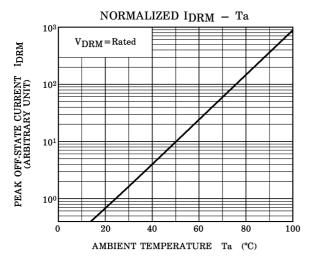


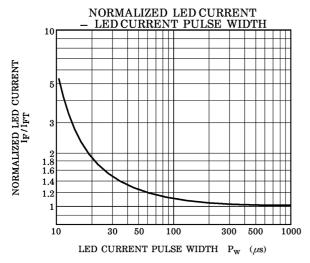


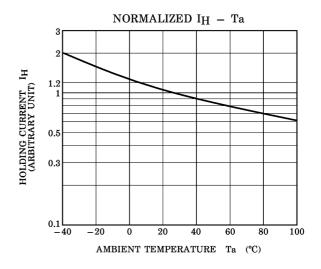


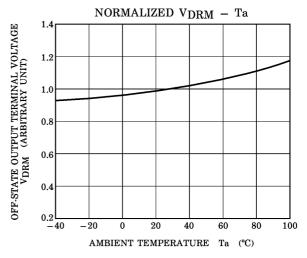
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